

Search Notes

Application/Control No.

10/672,381

Examiner

Phu K. Nguyen

Applicant(s)/Patent under
Reexamination

SHIOYA, HIROYUKI

Art Unit

2628

SEARCHED

Class	Subclass	Date	Examiner
345	426-428	9/18/2005	PN
	419	9/18/2005	PN
	423	9/18/2005	PN
update	search	9/5/2006	PN
update	search	3/14/2007	PN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
348	426	3/14/2007	PN
	427	3/14/2007	PN
	428	3/14/2007	PN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST search - BRDF, matrix, light, view, normal, reflectivity	9/18/2005	PN
Inventor Name searches	9/18/2005	PN
Update searches WEST, IEEE, ACM	9/18/2005	PN
Update searches WEST, IEEE, ACM	9/5/2006	PN
Update searches WEST, IEEE, ACM	3/14/2007	PN